



VERITAS



33. FED-Konferenz
24./25. September 2025 Lübeck

Entwicklung einer Deep-Space-Elektronik für ein optisches Instrument zur Venus-Kartierung

25.09.2025

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DLR – Institute für Weltraumforschung



National Aeronautics and Space Administration
Jet Propulsion Laboratory
California Institute of Technology



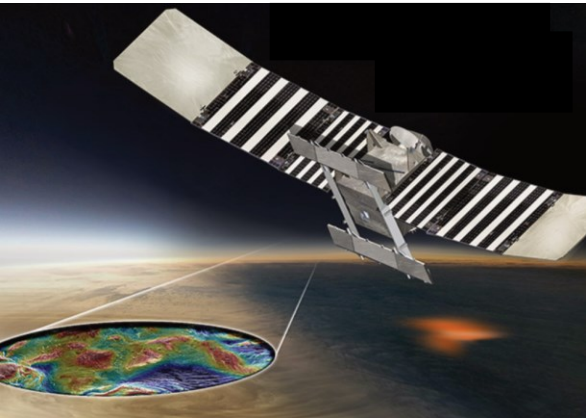
- General introduction to the Veritas & EnVision Missions
- The Instrument – VEM/ VenSpec-M
- VEM/ VenSpec-M Electronic
- PCB Assembly & Manufacturing for Space
- EEE Components selection for Space



Why is Venus so different from Earth?



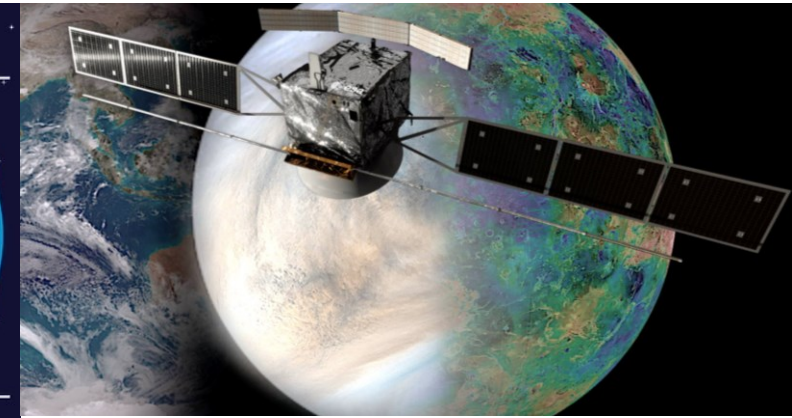
- **History** - How have the surface and interior evolved?
 - **Activity** - How geologically active is Venus?
 - **Climate** - How do geological processes shape atmosphere and climate?



Veritas
Credit: NASA

VENUS	EARTH
	
AGE ~4.6 BILLION YEARS	AGE ~4.6 BILLION YEARS
DIAMETER 12,104 KM	DIAMETER 12,756 KM

Credit: NASA



EnVision
Credit: ESA

Combining the surface mapping from VEM on VERITAS (NASA/JPL) and VenSpec-M on EnVision (ESA) will allow to look for change and increase the coverage of the planet

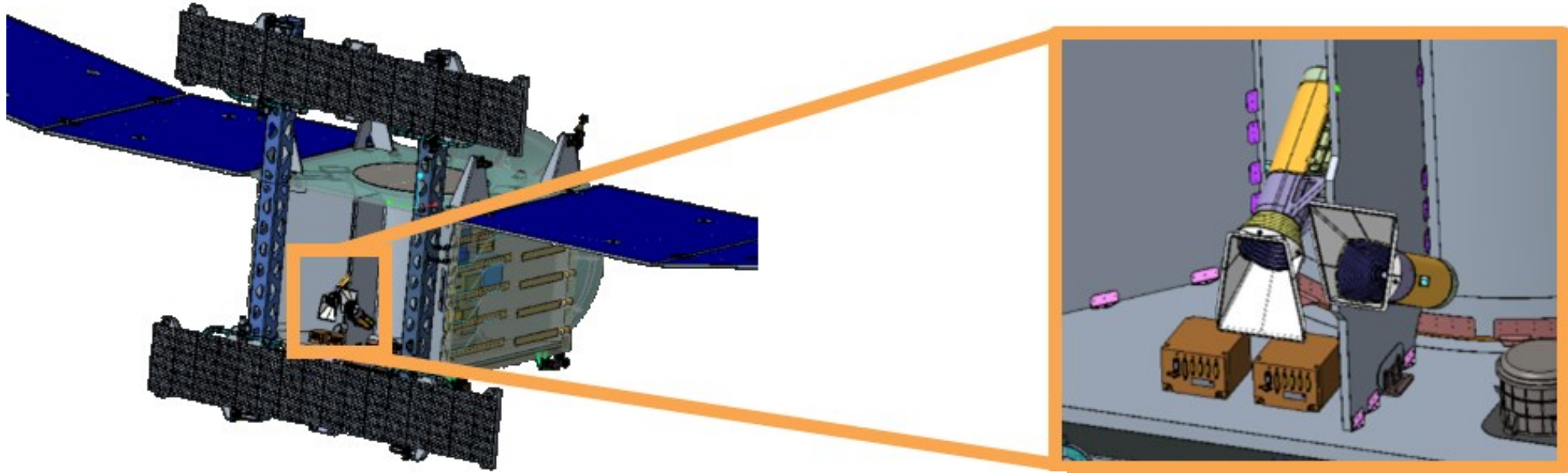
EnVision launch 2031

Veritas launch shifted from 2027 → 2029 → 2031 → 2032

<https://www.youtube.com/watch?v=W-UJ3yWpQns>

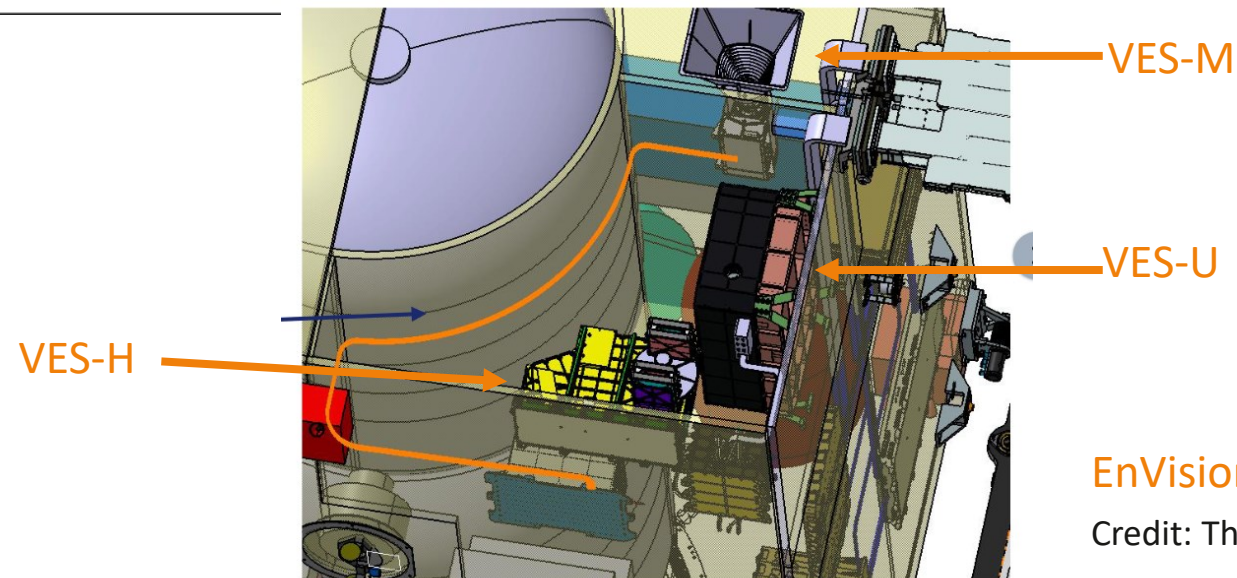


Instrument accommodation



Veritas

Credit: Lockheed Martin



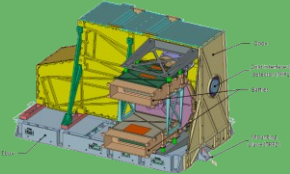
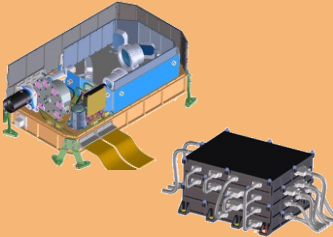
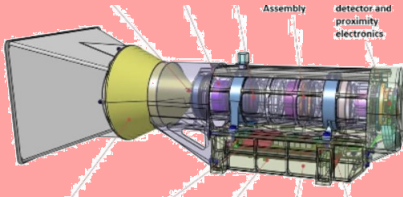
EnVision

Credit: Thales Alenia Space



The VenSpec Suite - EnVision



	 VenSpec-U Top clouds Sulfur species, UV absorber 
	 VenSpec-H Cloud composition Volcanic plumes CO, OCS, HF, HCl, SO₂, H₂O 
	 VenSpec-M Thermal emissions surface rock types 

Three spectrometers with a joint science & engineering team for a collaborative geologic and atmospheric research

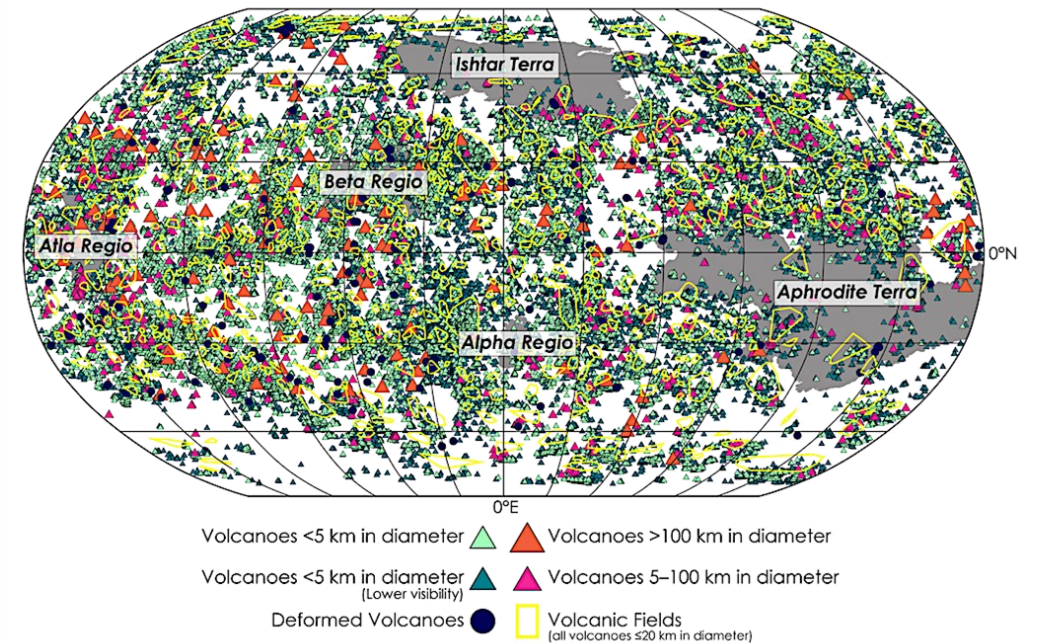
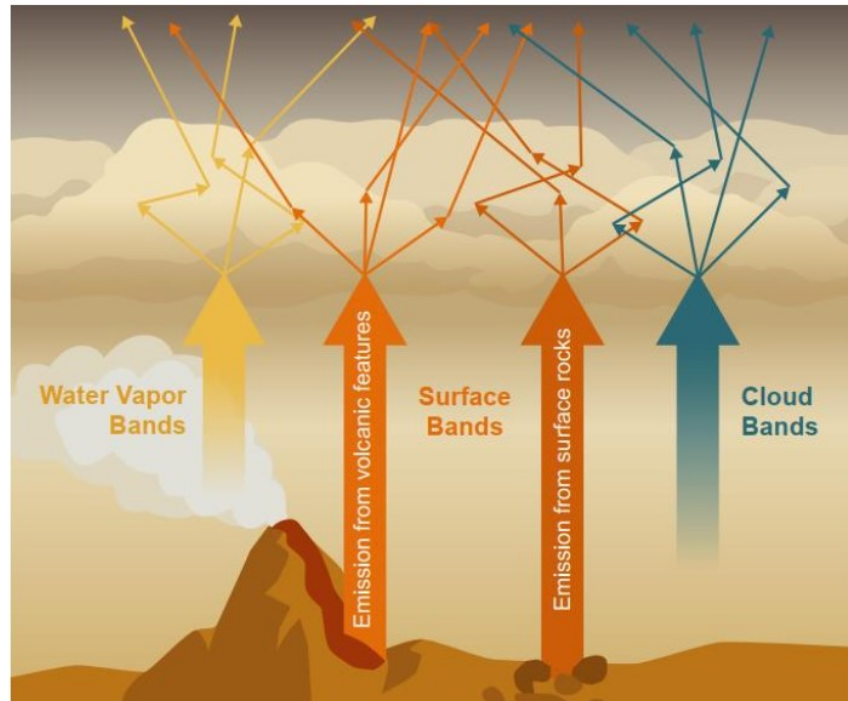
The Instrument VEM/VenSpec-M



VEM/VESM – Instrument Science Goals

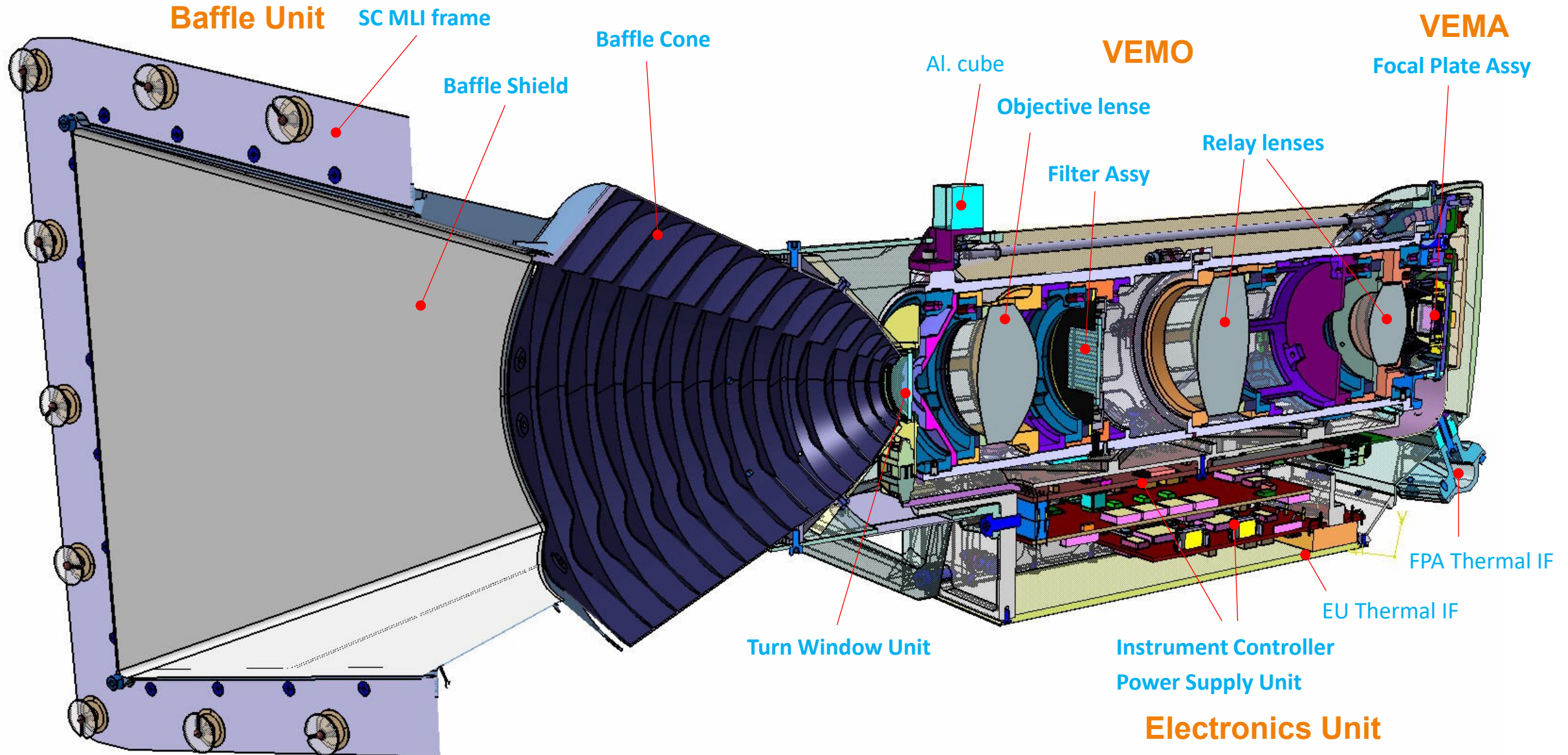


- Primary objective: global map of surface composition basalt vs granites with 70% coverage (Granite form in the presents of water)
- Second goal: volcanic activity (multiple looks on the same positions) expect 85000
- **Spatial resolution limited to 100 km** due to scattering in clouds



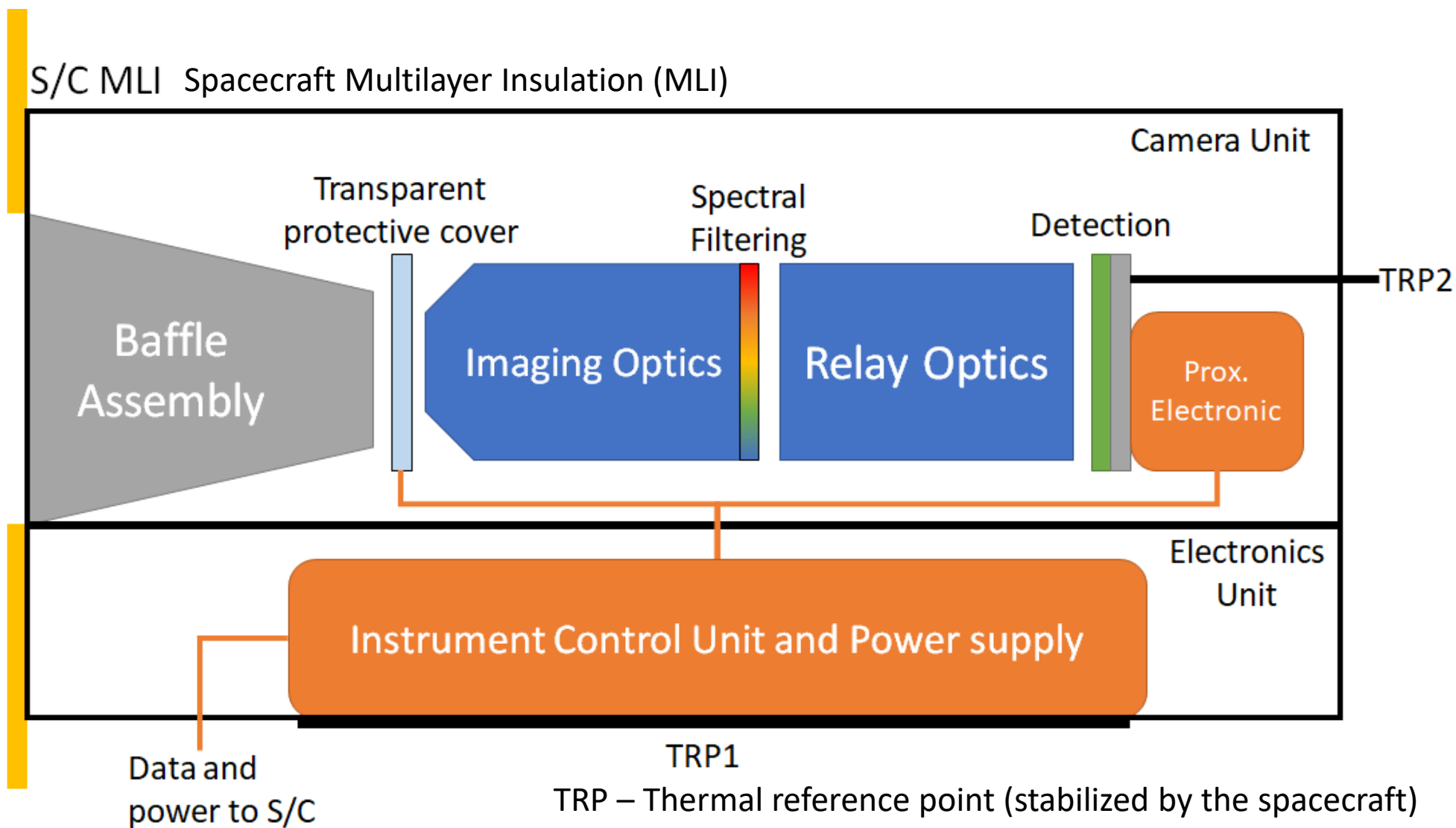


VEM/VESM Instrument





VEM/VESM Instrument - Functional block diagram



VEM/VESM Electronic



PCBs are the nerves and veins of the spacecraft



instruments



thermal
control



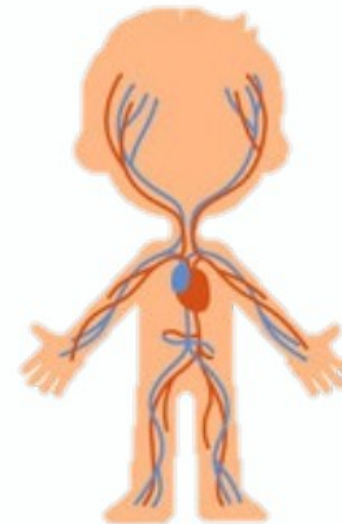
structures

mechanisms



power &
propulsion

power control
& distribution



data processing
& interfacing

PCBs are the **nerves and veins** of the spacecraft.

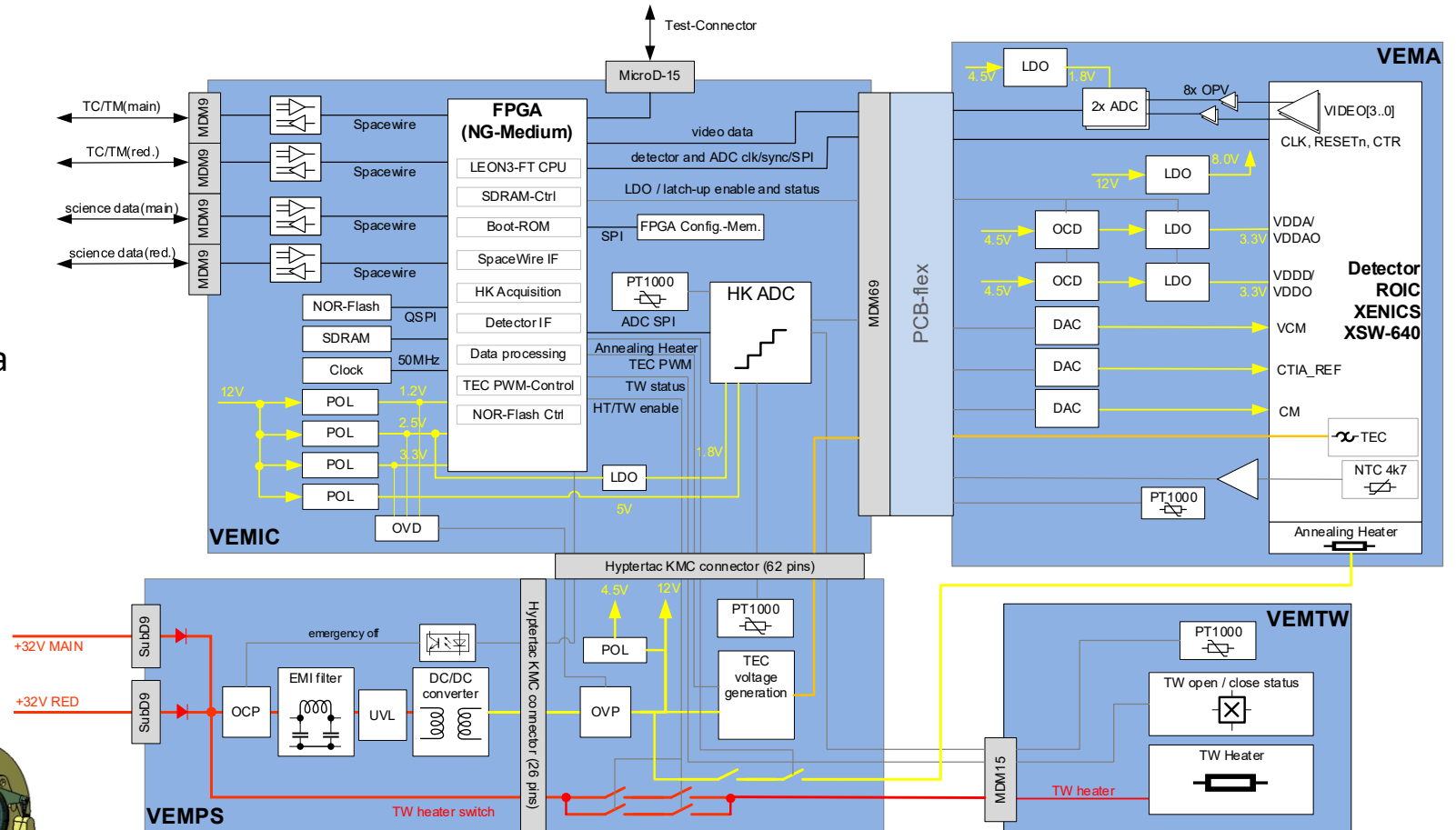
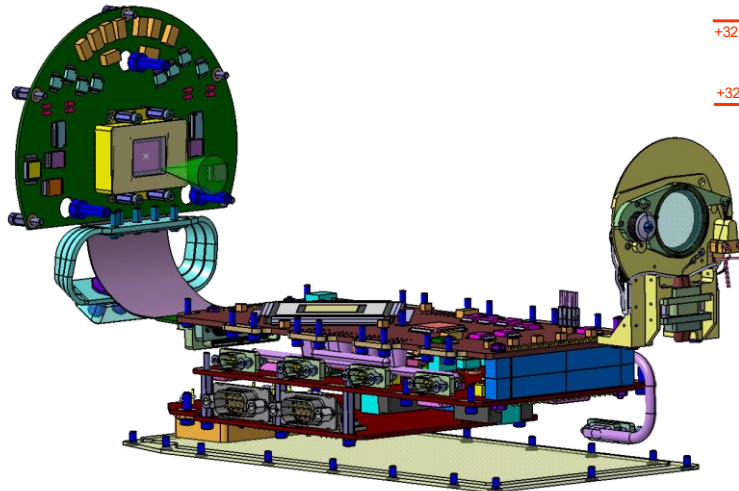
Credit: ESA



Electrical Architecture



- Hardware comprises 4 sub-systems: power-supply (VEMPS), instrument controller (VEMIC), analogue electronics (VEMA), TWU electronics (VEMTW)
- Power supply and instrument controller are implemented as a stack of 3 PCBs
- The analogue electronics is connected via a flex PCB to the instrument controller.



VEM Electrical Functional Block Diagram (29st Jan 2025)



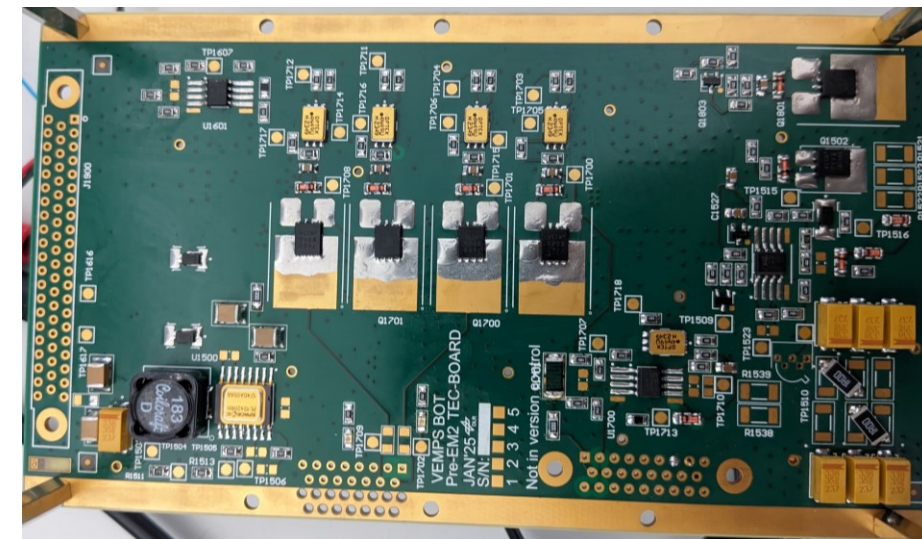
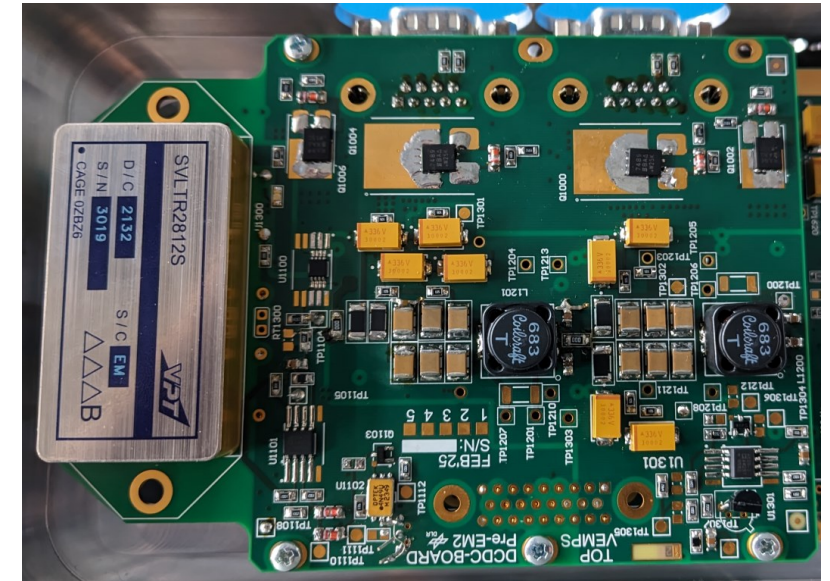
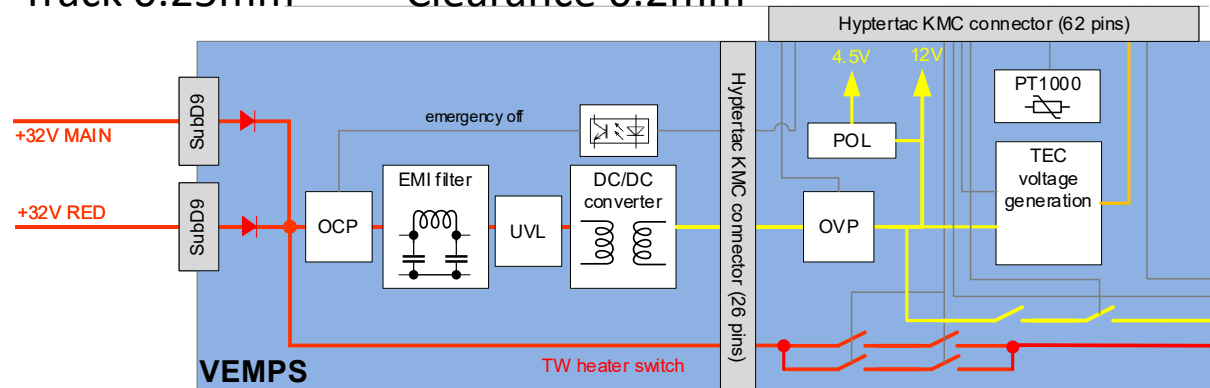
Power Supply Design - PCB

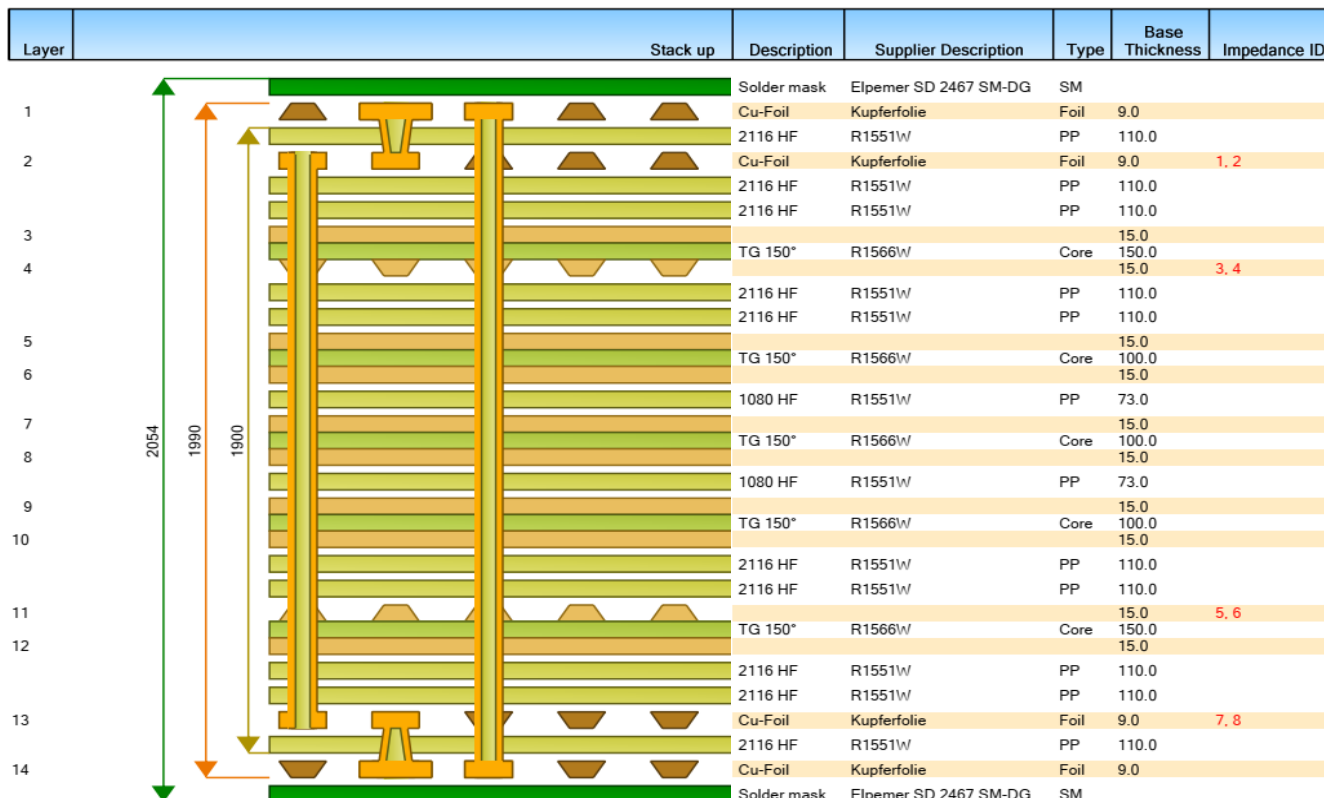


Lage	Lagenaufbau	Verarbeitete Dicke	εr	Herstellerbezeichnung	Type
1		25,000	2,700	LDI Matt Grün	Lack
		47,000		TZA HT	Folie
		57,125	3,900	R1650-M Typ 106	FR4
		57,125	3,900	R1650-M Typ 106	FR4
2		35,000			
		150,000	4,600	R1755-M	FR4
		35,000			
		35,000			
3		82,338	4,100	R1650-M Typ 1080	FR4
		82,338	4,100	R1650-M Typ 1080	FR4
		510,000	4,500	R1755-M	FR4
		82,338	4,100	R1650-M Typ 1080	FR4
4		82,338	4,100	R1650-M Typ 1080	FR4
		35,000			
		150,000	4,600	R1755-M	FR4
		35,000			
5		57,125	3,900	R1650-M Typ 106	FR4
		57,125	3,900	R1650-M Typ 106	FR4
		47,000		TZA HT	Folie
		25,000	2,700	LDI Matt Grün	Lack

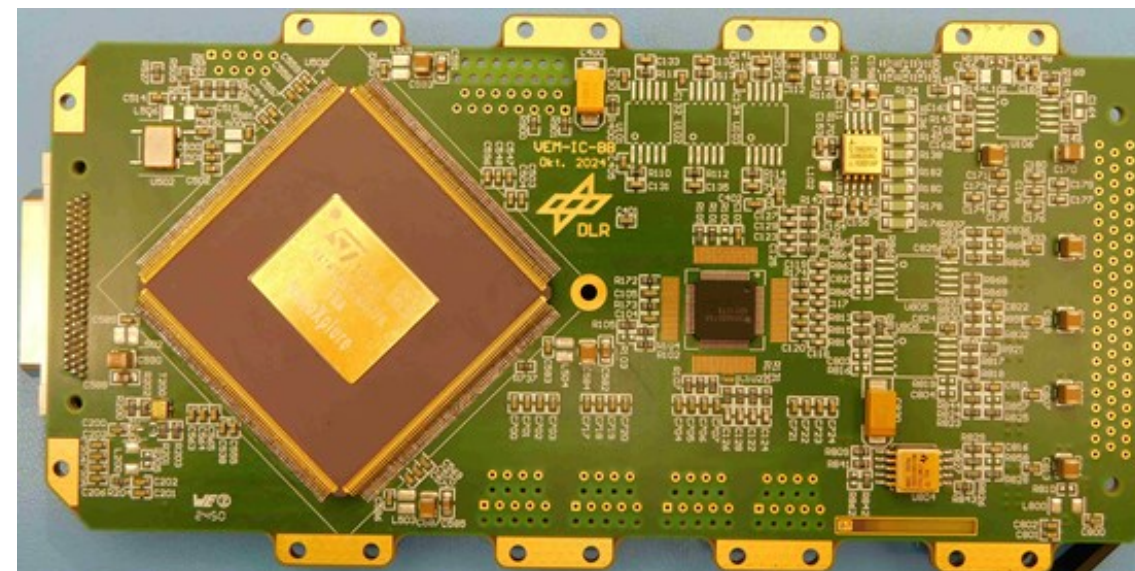
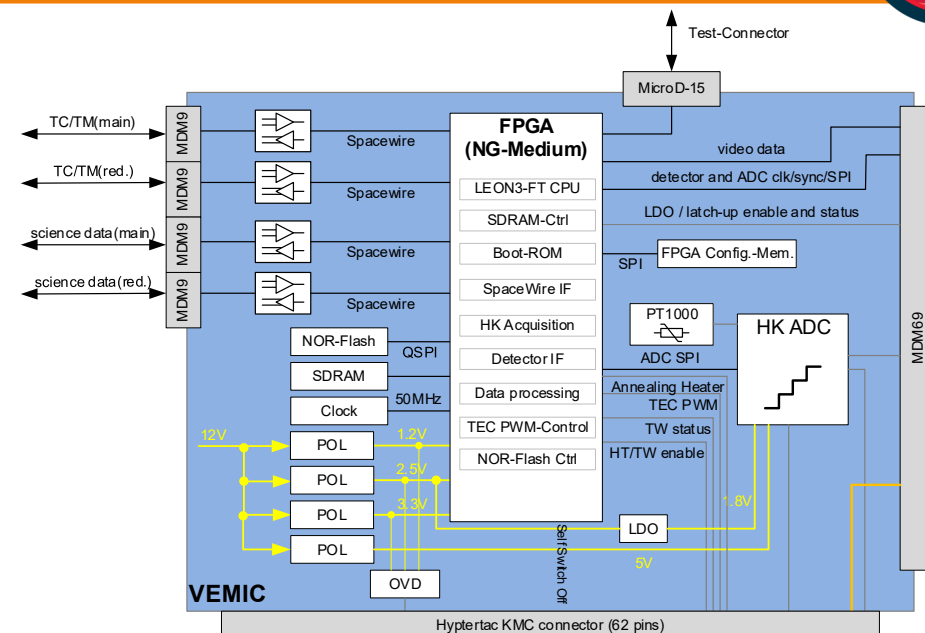
PTH 0.3/0.7mm
Track 0.25mm

Blind Vias 0.45/0.85mm
Clearance 0.2mm





PTH 0.25/0.5mm PTH2 0.25/0.55mm μVia 0.15/0.3
Outer Layer Tack 0.25mm /Clearance 0.3mm
Inner Layer Track 0.1mm/Clearance 0.15mm





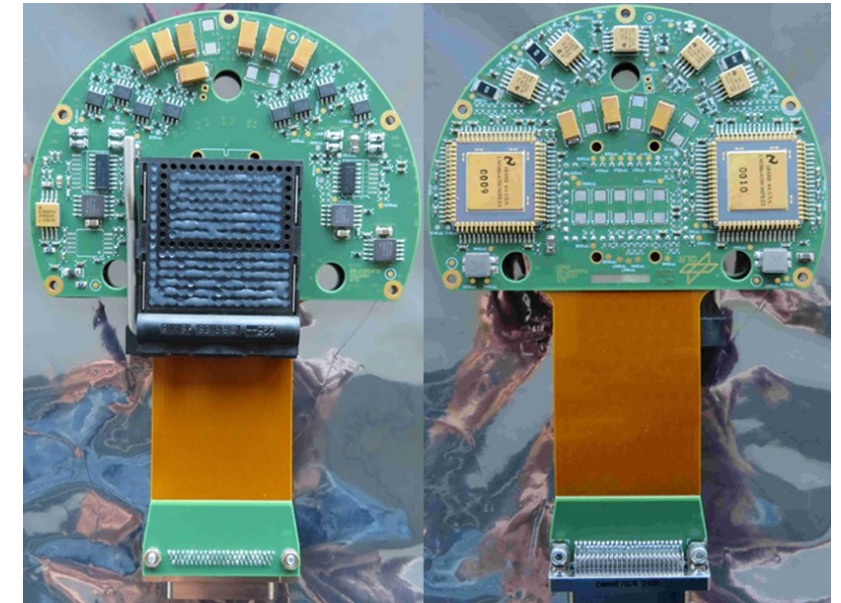
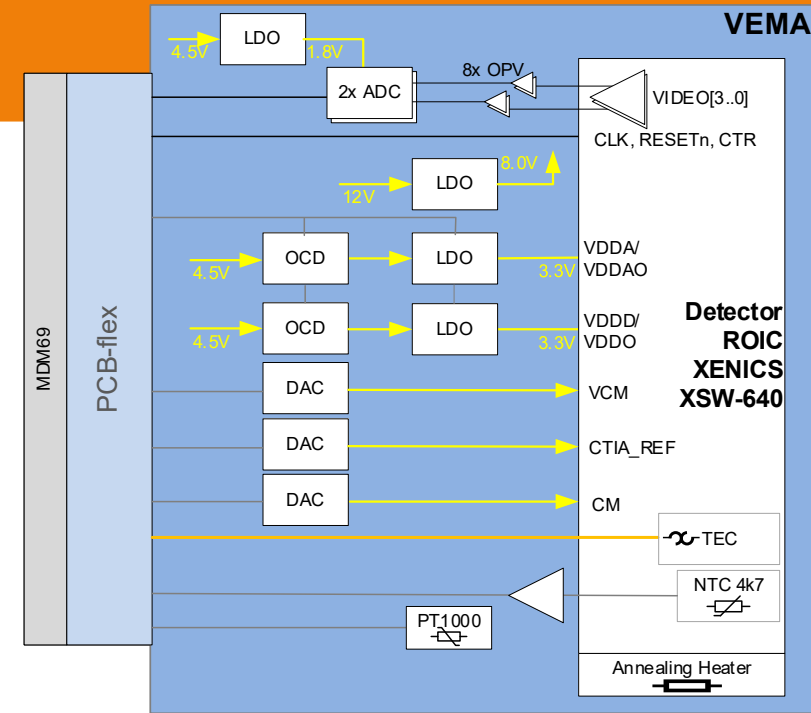
Detector Electronics Design - PCB



Layer	Stack up	Description	Type	Processed Thickness	εr	Copper Layer Type	Impedance ID
1		Soldermask		32,000	3,500		
		Cu-Foil		45,000		Signal	1, 2
2		2116 TG150° HF	PP	105,000	4,600		
		Cu-Foil		35,000		Plane	
3		2116 TG150° HF	PP	110,000	4,600		
		TG 150°	Core	16,000	4,600	Signal	3, 4
		3 x1080 TG 150° HF	PP	190,000	4,200		
4		75μm Polyimide	Core	16,000		Hatched	
5		2116 TG150° HF	PP	105,000	4,600	Signal	5, 6
		75μm Polyimide	Core	75,000	3,400		
6		75μm Polyimide	Core	75,000	3,400	Signal	
7		75μm Polyimide	Core	16,000		Hatched	
8		3 x1080 TG 150° HF	PP	190,000	4,200		
		TG 150°	Core	100,000	4,600	Signal	
9		2116 TG150° HF	PP	110,000	4,600		
		Cu-Foil		35,000		Plane	
10		2116 TG150° HF	PP	105,000	4,600		
		Cu-Foil		45,000		Signal	
		Soldermask		32,000	3,500		

Layer	Stack up	Description	Type	Processed Thickness	εr	Copper Layer Type	Impedance ID
4		25μm Polyimide/25μm Adhesive	Coverlay	40,000	3,600		
		75μm Polyimide	Core	16,000	3,400	Hatched	
5		75μm Polyimide	Core	16,000		Signal	1, 2
6		25μm Adh / 50μm PI / 25μm Adh	Bondply	95,000	3,600		
		75μm Polyimide	Core	16,000	3,400	Signal	
7		75μm Polyimide	Core	75,000	3,400	Hatched	
		25μm Polyimide/25μm Adhesive	Coverlay	40,000	3,600		

PTH 0.3/0.7mm PTH2 0.25/0.55mm μVia 0.1/0.35
 Outer Layer Tack 0.2mm Clearance 0.25mm
 Inner Layer Track 0.1mm Clearance 0.15mm





Main challenges during design phase

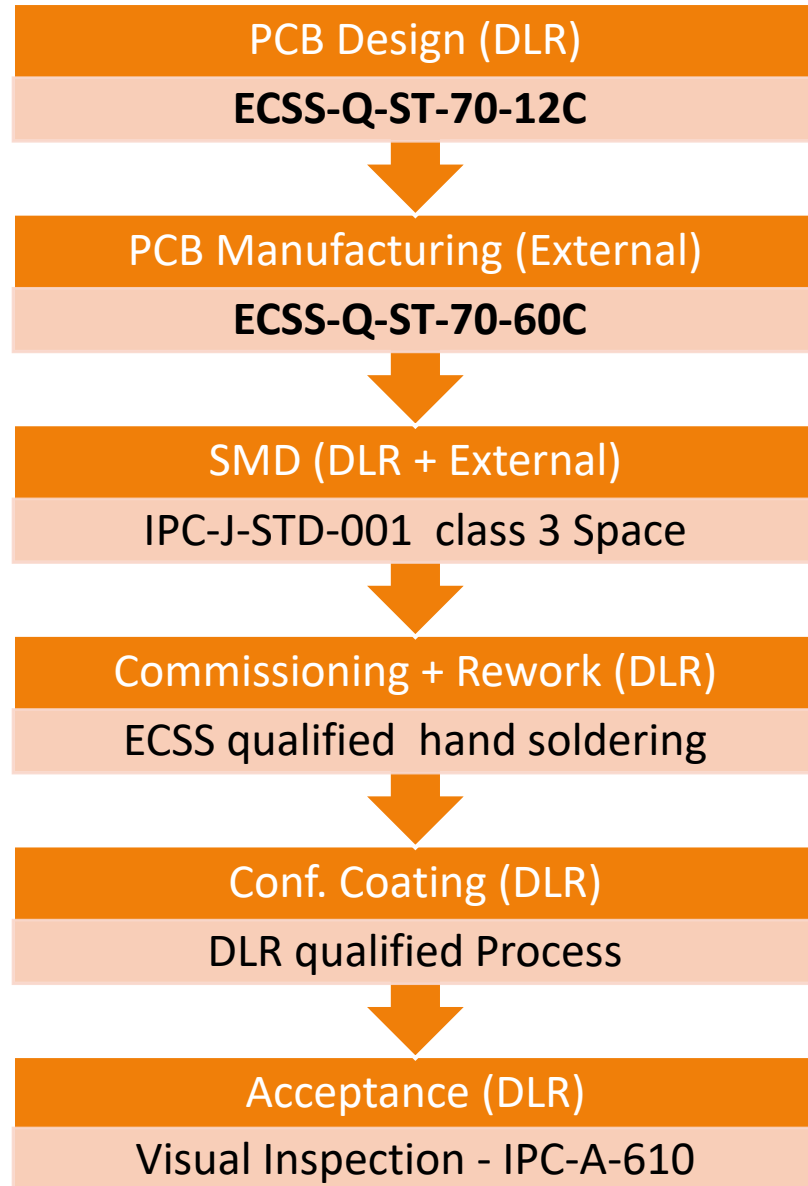


- Commercial detector failed radiation testing
 - Too many latch-ups during heavy ion testing
 - Need to change the detector → new qualification, change from digital to analog interface
- Hybrid DC/DC converter was seen as a major project risk from JPL
 - New hybrid DC/DC converter need to be chosen
 - Voltage changed from 5V -> 8.7V -> 12V
 - Different functionality (no EMI Filter, no OVP)
- FPGA was changed
 - Cost & power consumption
- Demanding and changing EMC requirements

PCB Assembly & Manufacturing



PCB Assembly & Manufacturing flow for the VEM/VESM Instrument



- PCB design and manufacturing according to ECSS
 - Material: Arlon 35N or VENTEC VT901.
- SMD based on IPC Class 3S to have more flexible facility
- DLR internal hand soldering by ECSS certified operators
- Verification (Life and Microsections) on critical packages
- Acceptance according to ECSS and IPC IPC-A-610



ESA qualified PCB manufactures



Lead time of up to > 40 weeks



A&P Lithos Chateaubourg
Qualification in progress

(Ciretec discontinued due to fire)

Credit: ESA



IPC qualified PCB for space



- PCB manufactured with IPC class 3s is possible
 - For NASA missions is the baseline
 - For ESA missions it is an option with extra process control and approval by ESA
- In general:
 - ESA will need visit and approve the manufacturer
 - Process qualification & lot of paper work
 - Process control and approval is managed by ESA
 - Extra coupon with microsections (ESA defined)
- ESA mission classes give a guideline how much work its need to be done

Class type	I	II	III	IV	V
Mission Criteria and Marking					
Criticality to Agency strategy (Flagship mission, International cooperation, Impact on ESA strategic goals, and image)	Extremely high Criticality	High Criticality	Medium Criticality	Low Criticality	Educational purposes
Marking					
Mission Objectives (Directorate priority and purpose, e.g in orbit demonstration, educational)	Extremely high Priority	High Priority	Medium Priority	Low Priority	Educational purposes
Marking					
Cost (Cost at Completion, Including Phase E1)	>700 M€	200 - 700M€	50 - 200M€	1- 50M€	< 1M€
Marking					
Mission Lifetime (Nominal mission life duration)	> 10 years	5-10 years	2-5 years	2 years - 3 Months	< 3 Months
Marking					
Mission Complexity (Design interfaces unique payloads, New technology development)	High	High to Medium	Medium	Medium to Low	Low
Marking					

I - Critical safety issue (e.g. manned missions, Space Situational Awareness, operations center)

II - Performances should be met whatever it takes

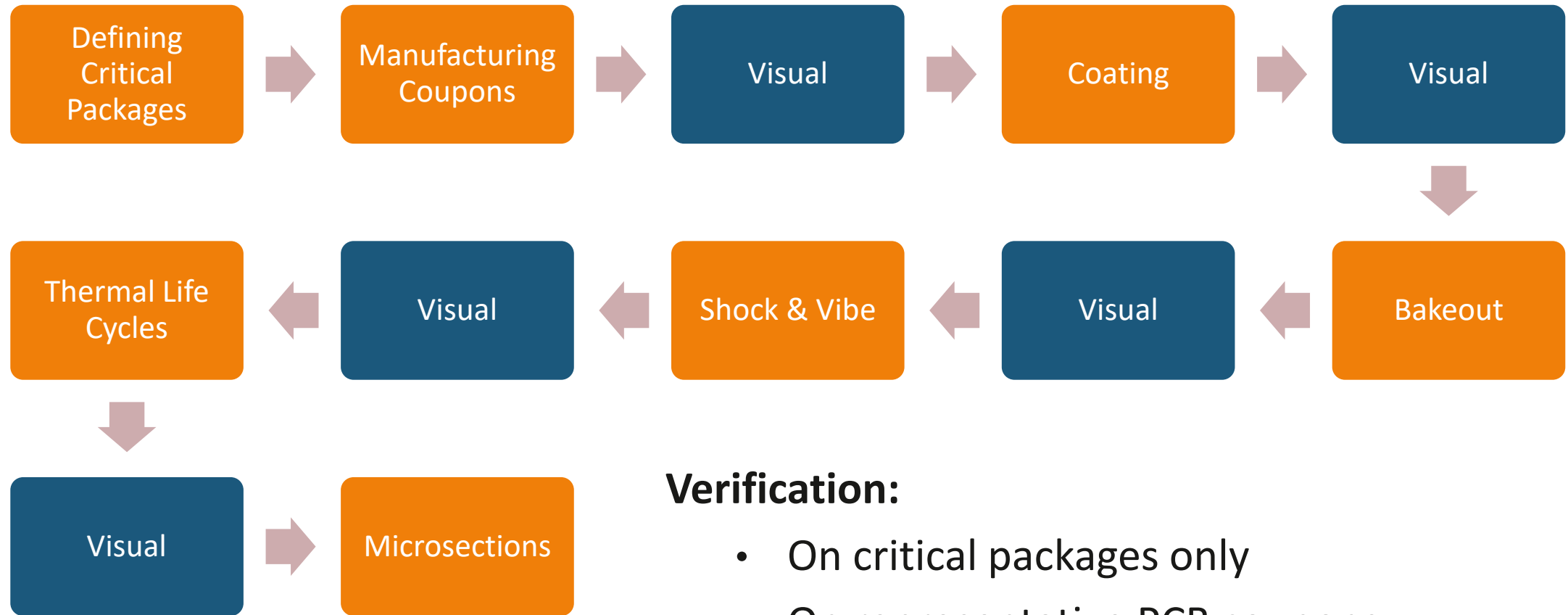
III - Finding the best compromise between risk and cost to deliver the mission

IV - Mission is designed according to a hard cost limit (affordability approach)

V - Almost full delegation to industry (e.g. newspace service contract, Public-Private Partnerships)



SMT Process and Qualification flow



Verification:

- On critical packages only
- On representative PCB coupons
- Mechanical Load
- Thermal Cycling
- Micro-sectioning



What are critical packages?



- Know history (heritage) and ESA and JPL lists
- Critical packages for VEM/VenSpec-M: 33 of 65
 - Eg: Flatpacks, Resistor/Capacitors ≤ 0603 & ≥ 2010 , QFP, TSOP
- Coupons needs to be similar to the PCB the packages will be used on
 - Material, Manufacturer, Layerstack
- Multiple packages on the coupon 5-10 (on all micro sectioning)
- Whole qualification takes month 3-4 months with margin 6 months
 - Eg.: 420 thermal cycling alone: ~ 30 days

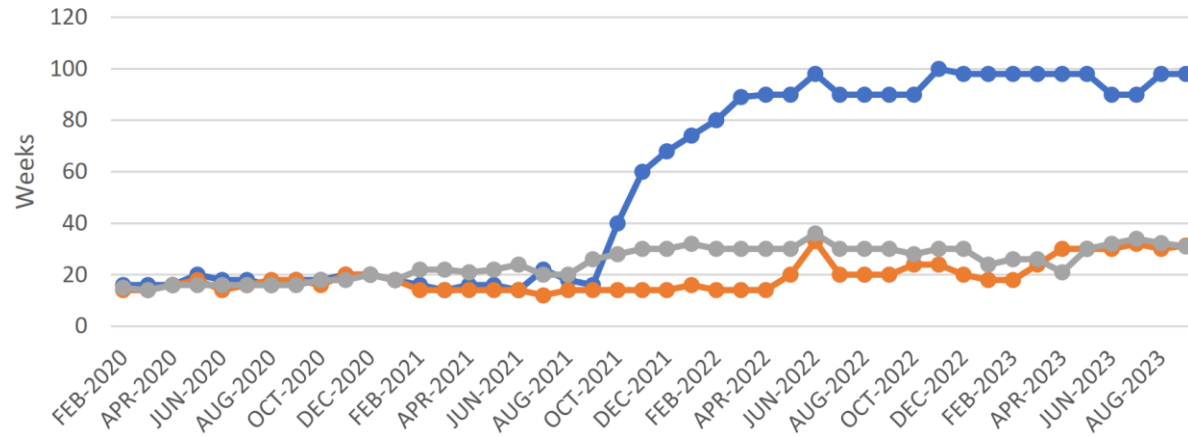
EEE Components



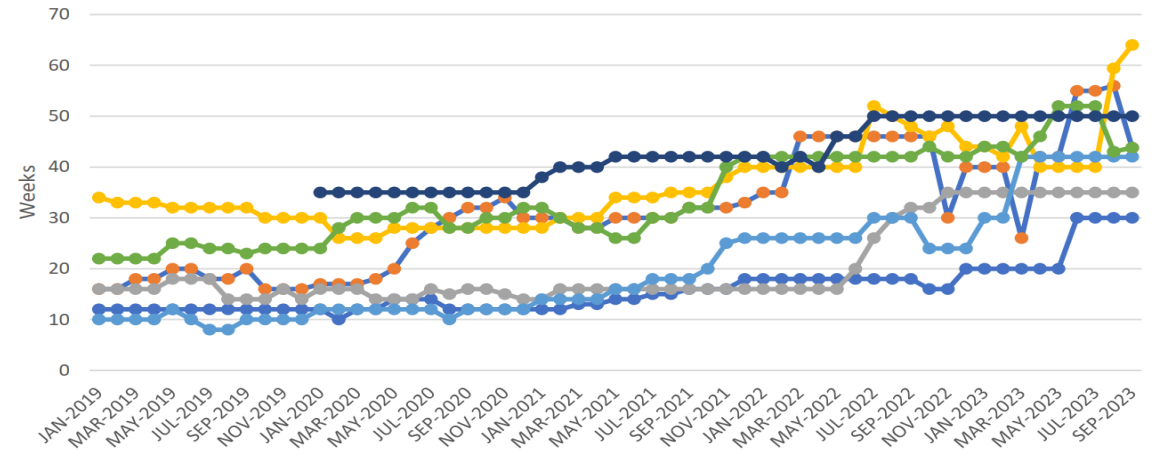
Space Component Lead Time



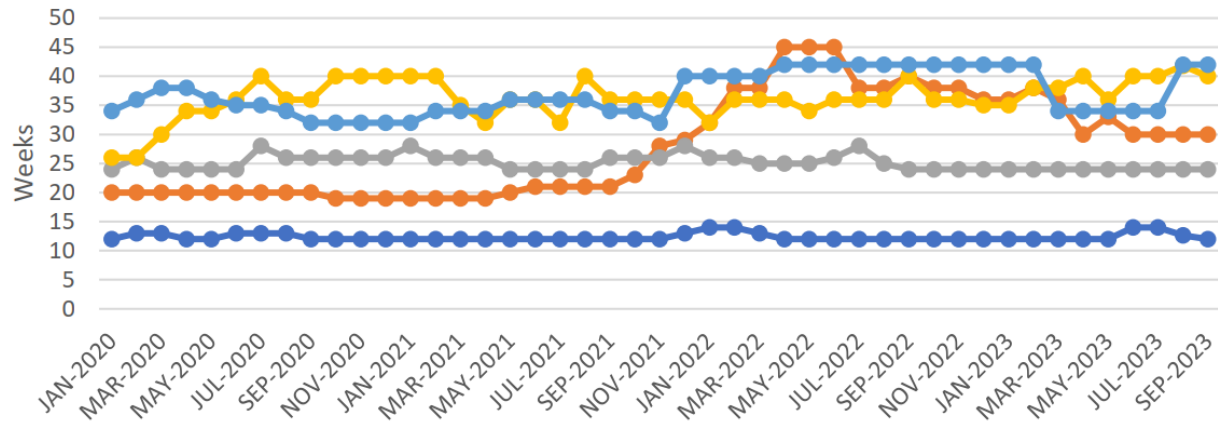
RESISTORS LEAD TIME



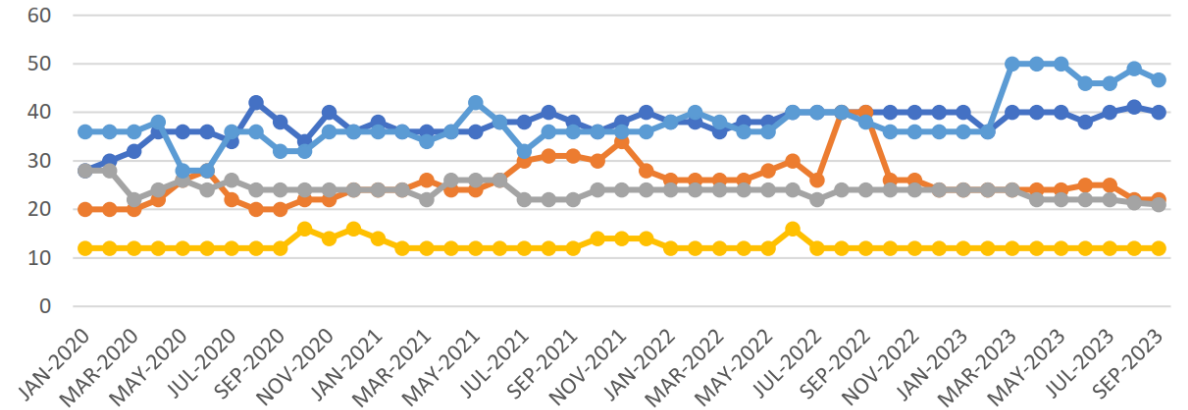
FPGAs lead time



Bipolar transistors lead time



Diodes lead time

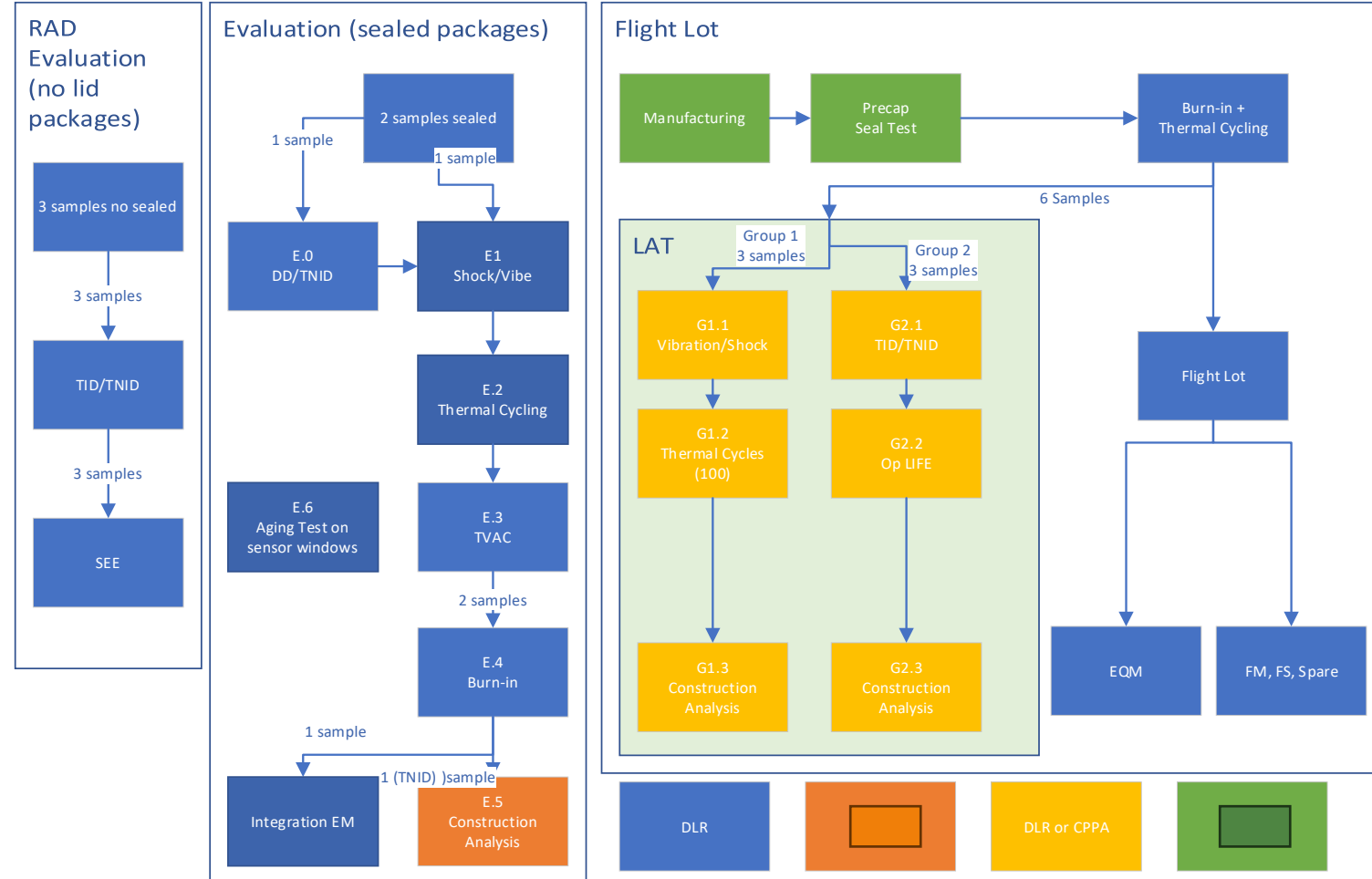
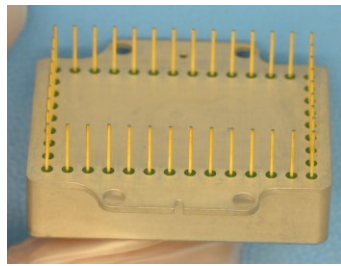
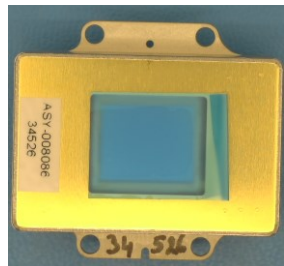




COTS Qualification for Space



- Only if there is no alternative or big numbers (new space, constellation)
- Evaluation campaign to demonstrated that your component works according to datasheet and your requirements (boundaries) in the mission environment
 - Duration a few months (limited availability for radiation facilities)



Questions?

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Challenges what ever



- Environment challenges
 - Radiation
 - Vacuum
 - Low Outgassing/cleanliness (optical instruments)
 - Thermal (-40 to 80°C)
 - Mechanical loads (during launch)
- Component challenges
 - Cleanliness
 - Reliability (life time, failure propagation)
 - Reliability-, Worst Case-, Part Stress-Analysis, FMEA, Part Level FMEA
 - Leadtime & Cost
 - Less complex and older circuits (limited amount of different circuits)
 - Often discreet circuits
 - Radhard